Park Systems AFM Workshop

Advance and Accuracy in Atomic Force Microscopy

NANOCHARACTERIZATION FOR MATERIALS SCIENCE

31 March, 2020 | Zagreb, Croatia
Ruđer Bošković Institute

schaefer

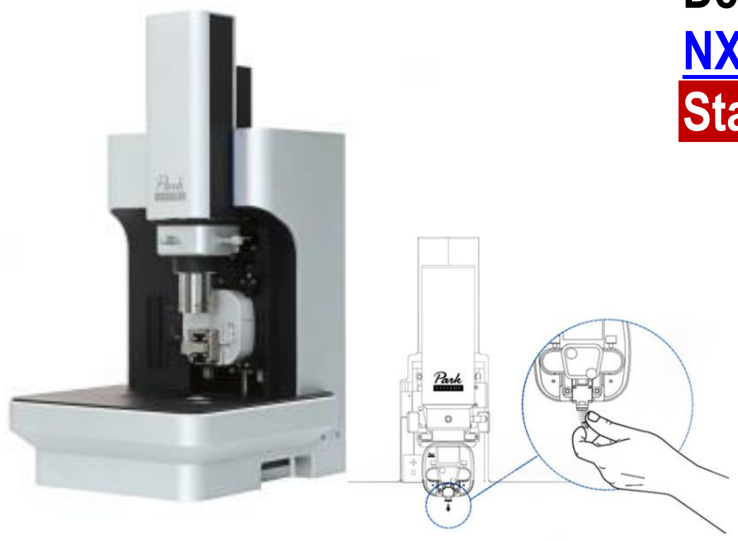
RB

Park
SYSTEMS

In collaboration with:

m. TEH
mjerne tehnologije d.o.o.

Demo session on specialist’s samples



Demo unit available:

NX10 model, Park Systems, South Korea

Standard configuration presented in Zagreb, Croatia

50 µm XY scanner

15 µm Z scanner

sample size (max.): 100 mm x 100 mm, thickness 20 mm

More details about NX10 model, please find HERE

The microscope *will be operated by Toni Moldovan,PhD*
AFM Applications Specialist, Schaefer S-E Europe

Operating modes available on the demo unit:

- True Non-Contact AFM, Basic Contact AFM
- PinPoint™ Nanomechanical Mapping (Deformation, Adhesion force, Adhesion energy,...)
- Intermittent (tapping) AFM
- Phase Imaging
- F/d spectroscopy, Force volume imaging

Sample Analysis Session:

- We estimate to be able to analyze approx.10 samples during the workshop
- Order of analysis will be based on order of registration with possible optimization based on sample types
- We will prioritize one sample per research group or department (in case of too many samples)

Registration Deadline, March 18, 2020

Registration contact data:

Claudia Moldovan, **Schaefer S-E** (including details about your sample): moldovan@schaefer-tec.com
Igor Zdrahal, **m TEH** (local contact): igor.zdrahal@mteh.hr